

# Reliability of Computer Systems

## Part 1: Basic Reliability Quantification

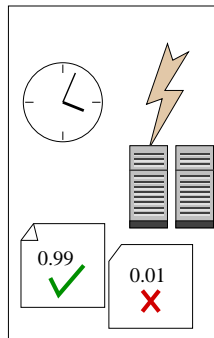
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29th July 2016

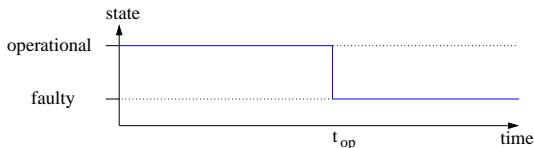
## Overview:

- Probabilities of fault free operation and failures
- Availability of a functionality
- Time aspects:
  - How long is a system operational / faultfree?
  - Mean time to failure, Mean time to repair.
  - Mission time?
- Influence of the system structure / complexity on reliability



## How long does a system operate without failures?

Expected operation time  $E(t_{op})$ , MTTF (Mean time to Failure)



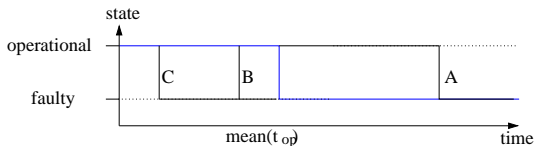
Example: A hard disk in a server is expected to work two years. A clever (?) strategy could be to replace it every two years by a new one.

# Reliability Measures

Example: A hard disk in a server is expected to work two years. A clever (?) strategy could be to replace it every two years by a new one.

Important: one should not trust in this period! These two years can be:

- **a mean value**, i.e. when three disks are in operation: 4, 1.5 and 0.5 years. Two out of three devices do not reach the two years :-)
- **a probabilistic measure**, e.g. 99% fail after two years



## How likely is a faultfree operation for a specified period?

Perspective:  $L$  ... lifetime,  $t_{op}$ , MTTF

At time  $t$ :

- P(operational at time  $t$ ):  $R(t) = P(L > t)$
- $R(t)$  is the probability that the lifetime of the device is longer than the time period  $t$
- $R(t)$  is the probability that the device is faultfree at time  $t$

# Reliability Measures

Reliability is the probability of a system performing its purpose adequately for the period of time intended under the operating conditions encountered<sup>1</sup>.

$$R(t) = P(L > t)$$

$L$  ... lifetime

$t$  ... time period, or current time when system runs since  $t_0 = 0$

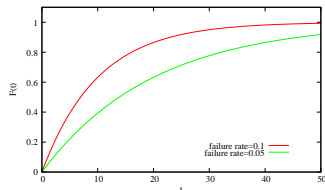
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<sup>1</sup>From A.L. Reibman, M. Veeraraghavan: Reliability Modeling: An Overview for Systems Designers. In: N. Suri, C.J. Walter, M.M. Hugue. Advances in Ultra-Dependable Distributed Systems, IEEE Computer Society Press, 1995

## Failure probability

$$F(t) = 1 - e^{-\lambda t}$$

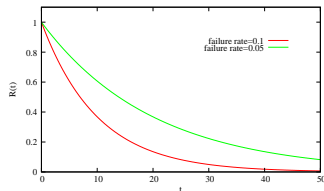
compares to a CDF



## Reliability

$$R(t) = 1 - F(t)$$

$$R(t) = e^{-\lambda t}$$



Parameter  $\lambda$ : failure rate, measured in  $\frac{1}{\text{time unit}}$ .

For example one failure per 10 years is expressed by  $0.1 \frac{1}{\text{year}}$

## Mean Time to Failure

Expected value of L:

$$MTTF = E(t) = \frac{1}{\lambda}$$

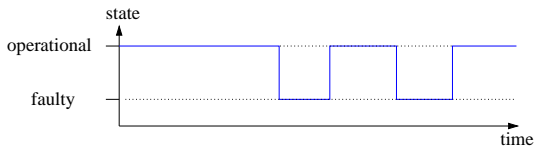
Mean Time to Failure is the expected time until a system fails.



## Availability

Q: How often is a system out of operation during a specified period?

A,  $A(t)$ : Availability is the probability that a system will be operational at a given time.



A: stationary case without any assumption on the time

## Availability

Observation of faulty and operational states requires to take repair (or any kind of recovery) into account.

Parameters:

- $\lambda$ : failure rate, and  $MTTF = \frac{1}{\lambda}$
- $\mu$ : repair rate, and  $MTTR = \frac{1}{\mu}$

$$A = \lim_{t \rightarrow \infty} A(t) = \frac{\mu}{\lambda + \mu}$$

$$A = \frac{MTTF}{MTTF + MTTR}$$

## Example (1/2)

### Single component, no repair

Failure rate  $\lambda = 0.5 \frac{1}{\text{year}}$ , MTTF = 2 years

$$R(t) = e^{-\lambda t}$$

t	10 d	1 month	$\frac{1}{2}$ year	1 year	2 years	3 years	5 years
R(t)	0.9864	0.9592	0.7788	0.6065	0.3679	0.2231	0.0821

These numbers tell us:

- A mission time shorter than the MTTF does not necessarily mean that the system is unlikely to fail.
- A longer operation than the MTTF leads to a very high failure probability
- For a mission time = MTTF:

$$R(\text{MTTF}) = R\left(\frac{1}{\lambda}\right) = e^{-1} = 0.37$$

## Example (2/2)

### Single component, with repair

$$\text{Failure rate } \lambda = 0.5 \frac{1}{\text{year}}$$

$$\text{Repair rate } \mu = 36.5 \frac{1}{\text{year}} \quad (10 \text{ days outage for repair})$$

$$\text{MTTR} = \frac{1}{\mu} = \frac{1}{36.5} \text{ year}$$

$$\text{MTTF} = 2 \text{ years}$$

Availability:

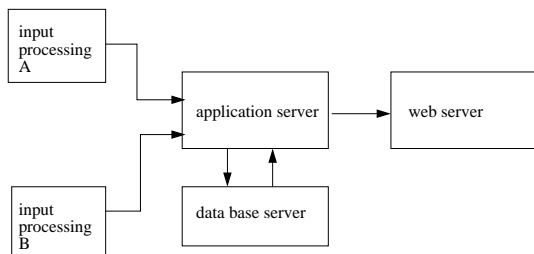
$$\begin{aligned} A &= \frac{\mu}{\lambda + \mu} \\ &= \frac{36.5}{0.5 + 36.5} = 0.9865 \end{aligned}$$

The same result is obtained by

$$\begin{aligned} A &= \frac{\text{MTTF}}{\text{MTTF} + \text{MTTR}} \\ &= \frac{2}{2 + \frac{1}{36.5}} = 0.9865 \end{aligned}$$

# System structure

Complex systems consists of many independent components that all can fail



Effects:

- Complexity increases the susceptibility against component faults
- The reliability of the system decreases with increasing complexity<sup>2</sup>

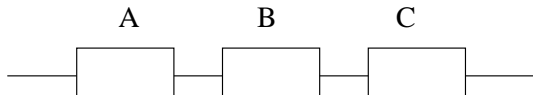
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<sup>2</sup>But this can be compensated by fault-tolerance techniques

# System structure

Complex System: Every component is required to work properly

Serial composition (RBD<sup>3</sup>): compares to an electrical circuit



A failure of any single component causes a system failure

$$R_{total} = R_A \times R_B \times R_C$$

$$F_{total} = 1 - ((1 - F_A) \times (1 - F_B) \times (1 - F_C))$$

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<sup>3</sup>Reliability Block Diagram

# System structure: serial composition

Example 1:

Three servers

- database server:  $R=0.999$ ,  $F= 0.001$
- application server:  $R=0.995$ ,  $F = 0.005$
- web server:  $R=0.99$ ,  $F=0.01$

$$\begin{aligned}R &= 0.999 \cdot 0.995 \cdot 0.99 = 0.984 \\F &= 0.016\end{aligned}$$

Example 2:

Parallel computer, composed of 500 blades (main boards)

$$R_{blade} = 0.9999, F_{blade} = 0.0001$$

$$\begin{aligned}R &= R_{blade}^{500} = 0.9512 \\F &= 0.0488\end{aligned}$$

# System structure: serial composition

Availability of a serial composition,  $N$  components

$$A = \frac{MTTF}{MTTF + MTTR}$$

$$A_{serial} = \prod_{i=1}^N A_i \quad A_i: \text{availability of component } i$$

Uniform system:  $A_i = A$  for all  $i$ ,  $A_{serial} = A^N$

Example:

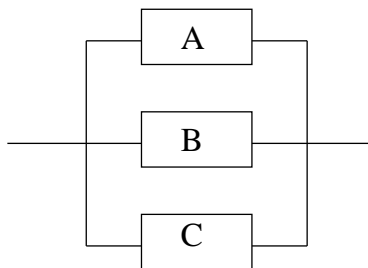
A	0.999	0.99	0.95	0.90	0.85
N=2	0.998	0.98	0.90	0.81	0.72
N=3	0.997	0.97	0.85	0.73	0.61
N=4	0.996	0.96	0.81	0.65	0.52
⋮	⋮	⋮	⋮	⋮	⋮
N=10	0.904	0.81	0.60	0.35	0.19



# System structure: parallel composition

Redundant systems: components are able to substitute each other

Parallel composition (RBD) compared to an electrical circuit



Only failures of all single components cause a system failure:

$$F_{total} = F_A \times F_B \times F_C$$

$$R_{total} = 1 - ((1 - R_A) \times (1 - R_B) \times (1 - R_C))$$

# System structure: parallel composition

Example: A database server that is duplicated

$$R_{dbserver} = 0.999, F_{dbserver} = 0.001$$

$$\begin{aligned} F &= F_{dbserver} \cdot F_{dbserver} = 0.001 \cdot 0.001 = 0.00001 \\ R &= 1 - F = 0.99999 \end{aligned}$$

# Summary of part 1

- Reliability can be quantified by measures:
  - Failure rate (empiric value)
  - Mean time to failure (MTTF, Expected life time)
  - Reliability (Probability of not failing)
  - Failure probability
  - Availability
  
- Reliability and failure probability depend on mission time of the system

# Summary of part 1 (cont.)

- Long running or critical computer applications (e.g. server applications) require
  - Either reliable components (with a low failure rate)
  - or repair during operation
  - even proactive replacement of components during operation
- System structure
  - Complexity (i.e. a high number of components that rely on each other) reduces reliability
  - Redundancy (systems that can substitute other) increases reliability